

ISOFACE™

ISO1H816G

Galvanic Isolated 8 Channel High-Side Switch

Datasheet

Revision 2.2, 2013-01-31

Power Management & Multimarket

Edition 2013-01-31

Published by Infineon Technologies AG 81726 Munich, Germany © 2013 Infineon Technologies AG All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.



Revision History						
Page or Item	Subjects (major changes since previous revision)					
Revision 2.2, 2	013-01-31					
Page 13	Page 13, Table 4.1 Extended operating temperature added					
Revision 2.1						
Page 18	Page 18, 4.8 SPI Timing, t _{CSD} updated					
Revision 2.0						
all	Final Datasheet					

Trademarks of Infineon Technologies AG

AURIXTM, C166TM, Canpaktm, CIPOSTM, CIPURSETM, Econopacktm, CoolMostm, CoolSettm, Corecontroltm, Crossavetm, Davetm, DI-Poltm, EasyPIMTM, Econobridgetm, Econopualtm, Econopimtm, Econopacktm, Eicedrivertm, eupectm, FCostm, Hitfettm, Hybridpacktm, I²rftm, Isofacetm, Isopacktm, MIPaqtm, Modstacktm, my-dtm, NovalithICtm, OptiMostm, Origatm, Powercodetm; Primariontm, Primepacktm, Primestacktm, Pro-Siltm, Profettm, Rasictm, Reversavetm, Satrictm, Siegettm, Sindriontm, Sipmostm, Smartlewistm, Solid Flashtm, Tempfettm, thinq!tm, Trenchstoptm, Tricoretm.

Other Trademarks

Advance Design System™ (ADS) of Agilent Technologies, AMBA™, ARM™, MULTI-ICE™, KEIL™, PRIMECELL™, REALVIEW™, THUMB™, µVision™ of ARM Limited, UK. AUTOSAR™ is licensed by AUTOSAR development partnership. Bluetooth™ of Bluetooth SIG Inc. CAT-iq™ of DECT Forum. COLOSSUS™, FirstGPS™ of Trimble Navigation Ltd. EMV™ of EMVCo, LLC (Visa Holdings Inc.). EPCOS™ of Epcos AG. FLEXGO™ of Microsoft Corporation. FlexRay™ is licensed by FlexRay Consortium. HYPERTERMINAL™ of Hilgraeve Incorporated. IEC™ of Commission Electrotechnique Internationale. IrDA™ of Infrared Data Association Corporation. ISO™ of INTERNATIONAL ORGANIZATION FOR STANDARDIZATION. MATLAB™ of MathWorks, Inc. MAXIM™ of Maxim Integrated Products, Inc. MICROTEC™, NUCLEUS™ of Mentor Graphics Corporation. MIPI™ of MIPI Alliance, Inc. MIPS™ of MIPS Technologies, Inc., USA. muRata™ of MURATA MANUFACTURING CO., MICROWAVE OFFICE™ (MWO) of Applied Wave Research Inc., OmniVision™ of OmniVision Technologies, Inc. Openwave™ Openwave Systems Inc. RED HAT™ Red Hat, Inc. RFMD™ RF Micro Devices, Inc. SIRIUS™ of Sirius Satellite Radio Inc. SOLARIS™ of Sun Microsystems, Inc. SPANSION™ of Spansion LLC Ltd. Symbian™ of Symbian Software Limited. TAIYO YUDEN™ of Taiyo Yuden Co. TEAKLITE™ of CEVA, Inc. TEKTRONIX™ of Tektronix Inc. TOKO™ of TOKO KABUSHIKI KAISHA TA. UNIX™ of X/Open Company Limited. VERILOG™, PALLADIUM™ of Cadence Design Systems, Inc. VLYNQ™ of Texas Instruments Incorporated. VXWORKS™, WIND RIVER™ of WIND RIVER SYSTEMS, INC. ZETEX™ of Diodes Zetex Limited.

Last Trademarks Update 2011-11-11



ISOFACETM ISO1H816G

Coreless Transformer Isolated Digital Output 8 Channel 0.625 A High-Side Switch

Product Highlights

- · Coreless transformer isolated data interface
- Galvanic isolation
- 8 High-side output switches 1.2A
- µC compatible 8-bit serial peripheral

Infineon Ison Ison

Features

- Interface CMOS 3.3/5V operation compatible
- Serial Interface
- · High common mode transient immunity
- Short circuit protection
- · Maximum current internally limited
- · Overload protection
- Overvoltage protection (including load dump)
- Undervoltage shutdown with autorestart and hysteresis
- · Switching inductive loads
- · Common output disable pin
- · Thermal shutdown with restart
- Thermal independence of seperate channels
- Common diagnostic output for overtemperature
- ESD protection
- Loss of GNDbb and loss of V_{bb} protection
- Very low standby current
- · Reverse battery protection
- Isolated return path for DIAG signal
- · RoHS compliant

Typical Application

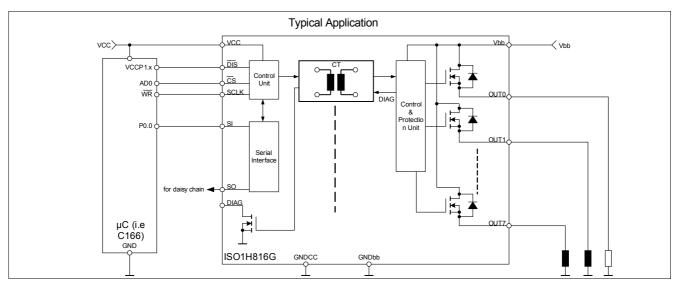
- Isolated switch for industrial applications (PLC)
- All types of resistive, inductive and capacitive loads
- µC compatible power switch for 24V DC applications
- · Driver for solenoid, relays and resistive loads

Description

The ISO1H816G is a galvanically isolated 8 bit data interface in PG-DSO-36 package that provides 8 fully protected high-side power switches that are able to handle currents up to 1.2 A.

An serial μC compatible interface allows to connect the IC directly to a μC system. The input interface is designed to operate with 3.3/5V CMOS compatible levels.

The data transfer from input to output side is realized by the integrated Coreless Transformer Technology.



Туре	On-state Resistance	Package
ISO1H816G	200m $Ω$	PG-DSO36

Datasheet 4 Revision 2.2, 2013-01-31



Pin Configuration and Functionality

1 Pin Configuration and Functionality

1.1 Pin Configuration

		T
Pin	Symbol	Function
1	N.C.	Not connected
2	VCC	Positive 3.3/5V logic supply
3	DIS	Output disable
4	CS	Chip select
5	SCLK	Serial Clock
6	SI	Serial Data input
7	N.C.	Not connected
8	N.C.	Not connected
9	N.C.	Not connected
10	N.C.	Not connected
11	N.C.	Not connected
12	N.C.	Not connected
13	SO	Serial Data Output
14	DIAG	Common diagnostic output for overtemperature
15	GNDCC	Input logic ground
16	N.C.	Not connected
17	N.C.	Not connected
18	N.C.	Not connected
19	GNDbb	Output driver ground
20	N.C	Not connected
21	OUT7	High-side output of channel 7
22	OUT7	High-side output of channel 7
23	OUT6	High-side output of channel 6
24	OUT6	High-side output of channel 6
25	OUT5	High-side output of channel 5
26	OUT5	High-side output of channel 5
27	OUT4	High-side output of channel 4
28	OUT4	High-side output of channel 4
29	OUT3	High-side output of channel 3
30	OUT3	High-side output of channel 3
31	OUT2	High-side output of channel 2
32	OUT2	High-side output of channel 2
33	OUT1	High-side output of channel 1
34	OUT1	High-side output of channel 1
35	OUT0	High-side output of channel 0
36	OUT0	High-side output of channel 0
TAB	Vbb	Positive driver power supply voltage
	1	1

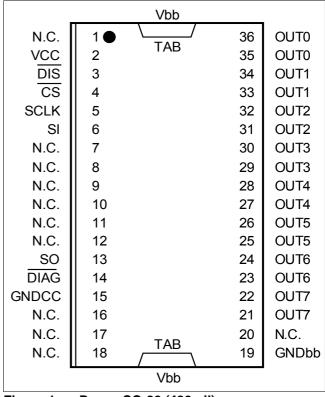


Figure 1 Power SO-36 (430mil)

Datasheet 5 Revision 2.2, 2013-01-31



Pin Configuration and Functionality

1.2 Pin Functionality

VCC (Positive 3.3/5V logic supply)

The VCC supplies the input interface that is galvanically isolated from the output driver stage. The input interface can be supplied with 5V.

DIS (Output disable)

The high-side outputs OUT0...OUT7 can be immediately switched off by means of the low active pin DIS that is an asynchronous signal. The input registers are also reset by the DIS signal. The output remains switched off after low-high transient of DIS, till new data is written into the input interface. Current Sink to GNDCC

CS (Chip select)

The system microcontroller selects the ISO1H816G by means of the low active pin $\overline{\text{CS}}$ to activate the interface. Current Source to VCC

SCLK (Serial shift clock)

SCLK (serial clock) is used to synchronize the data transfer between the master and the ISO1H816G. Data present at the SI pin are latched on the rising edge of the serial clock input, while data at the SO pin is updated after the falling edge of SCLK in serial mode. Current Source to VCC

SI (Serial data input)

This pin is used to transfer data into the device. Data is latched on the rising edge of the serial clock. Current Sink to GNDCC

SO (Serial data output)

This pin is used when the serial interface is activated. SO can be connected to a serial input of a further IC to built a daisy-chain configuration. It is only activated if $\overline{\text{CS}}$ is in low state, otherwise this output is in high impedance state.

DIAG (Common diagnostic output for overtemperature)

The low active DIAG signal contains the OR-wired information of the separated overtemperature detection units for each channel. The output pin DIAG provides an open drain functionality that. A current source is also connected to the pin DIAG. In normal operation the signal DIAG is high. When overtemperature or Vbb below ON-Limit is detected the signal DIAG changes to low.

GNDCC (Ground for VCC domain)

This pin acts as the ground reference for the input interface that is supplied by VCC.

GNDbb (Output driver ground domain)

This pin acts as the ground reference for the output driver that is supplied by Vbb.

OUT0 ... OUT7 (High side output channel 0 ... 7)

The output high side channels are internally connected to Vbb and controlled by the corresponding data input.

TAB (Vbb, Positive supply for output driver)

The heatslug is connected to the positive supply port of the output interface.



Blockdiagram

Blockdiagram 2

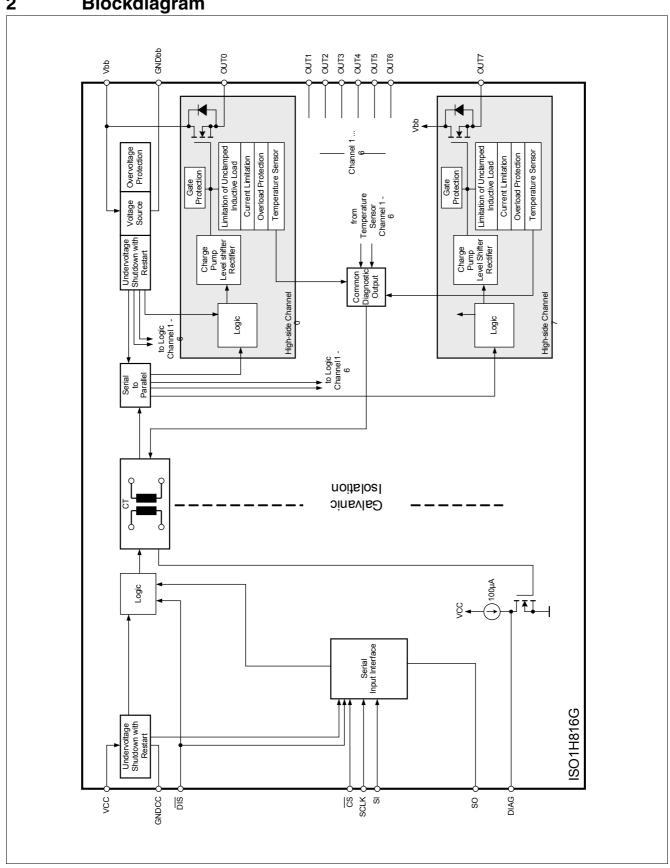


Figure 2 **Blockdiagram**



3 Functional Description

3.1 Introduction

The ISOFACE ISO1H816G includes 8 high-side power switches that are controlled by means of the integrated compatible SPI interface. The OUT0...OUT7 are controlled by the data of the serial input SI. The IC can replace 8 optocouplers and the 8 high-side switches in conventional I/O-Applications as a galvanic isolation is implemented by means of the integrated coreless transformer technology. The µC compatible interfaces allow a direct connection to the ports of a microcontroller without the need for other components. Each of the 8 high-side power switches is against short to Vbb. overtemperature and against overvoltage by an active zener clamp.

The diagnostic logic on the power chip recognizes the overtemperature information of each power transistor. The information is send via the internal coreless transformer to the pin DIAG at the input interface.

3.2 Power Supply

The IC contains 2 galvanic isolated voltage domains that are independent from each other. The input interface is supplied at VCC and the output stage is supplied at Vbb. The different voltage domains can be switched on at different time. The output stage is only enabled once the input stage enters a stable state.

3.3 Output Stage

Each channel contains a high-side vertical power FET that is protected by embedded protection functions.

The continuous current for each channel is 1.2A (all channels ON).

3.3.1 Output Stage Control

Each output is independently controlled by an output latch and a common reset line via the pin DIS that disables all eight outputs and reset the latches. Serial data input (SI) is read on the rising edge of the serial clock SCLK. A logic high input data bit turns the respective output channel ON, a logic low data bit turns it OFF. CS must be low whilst shifting all the serial data into the device. A low-to-high transition of CS transfers the serial data input bits to the output buffer.

3.3.2 Power Transistor Overvoltage Protection

Each of the eight output stages has its own zener clamp that causes a voltage limitation at the power transistor when solenoid loads are switched off. V_{ON} is then clamped to 47V (min.).

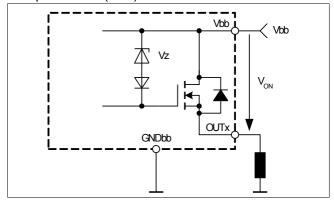


Figure 3 Inductive and overvoltage output clamp (each channel)

Energy is stored in the load inductance during an inductive load switch-off.

$$E_L = 1/2 \times L \times I_L^2$$

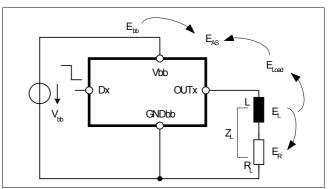


Figure 4 Inductive load switch-off energy dissipation (each channel)

While demagnetizing the load inductance, the energy dissipation in the DMOS is

$$E_{AS} = E_{bb} + E_L - E_R = V_{ON(CL)} \times i_L(t)dt$$

with an approximate solution for $R_1 > 0\Omega$::

$$E_{AS} = \frac{I_L \times L}{2 \times R_L} \times (V_{bb} + |V_{ON(CL)}|) \times ln \left(1 + \frac{I_L \times R_L}{|V_{ON(CL)}|}\right)$$



3.3.3 Power Transistor Overcurrent Protection

The outputs are provided with a current limitation that enters a repetitive switched mode after an initial peak current has been exceeded. The initial peak short circuit current limit is set to $I_{L(SCp)}$ at T_j = 125°C. During the repetitive mode short circuit current limit is set to $I_{L(SCr)}$. If this operation leads to an overtemperature condition, a second protection level (T_j > 135°C) will change the output into a low duty cycle PWM (selective thermal shutdown with restart) to prevent critical chip temperatures.

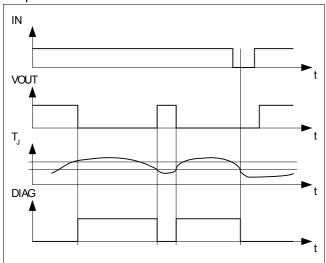


Figure 5 Overtemperature detection

The following figures show the timing for a turn on into short circuit and a short circuit in on-state. Heating up of the chip may require several milliseconds, depending on external conditions.

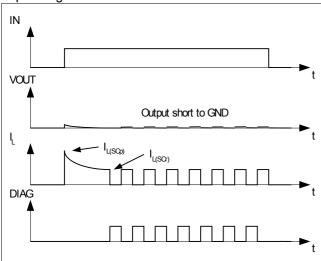


Figure 6 Turn on into short circuit, shut down by overtemperature, restart by cooling

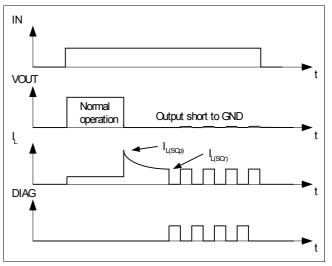


Figure 7 Short circuit in on-state, shut down down by overtemperature, restart by cooling

3.4 Common Diagnostic Output

The overtemperature detection information are ORwired in the common diagnostic output block. The information is send via the integrated coreless transformer to the input interface. The output stage at pin DIAG has an open drain functionality combined with a current source.

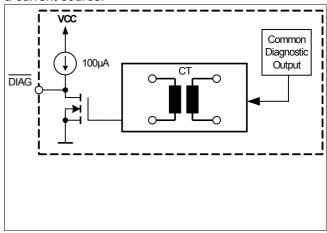


Figure 8 Common diagnostic output



3.5 Serial Interface

The ISO1H816G contains a serial interface that can be directly controlled by the microcontroller output ports.

3.5.1 SPI Signal Description

 $\overline{\text{CS}}$ - Chip select. The system microcontroller selects the ISO1H816G by means of the $\overline{\text{CS}}$ pin. Whenever the pin is in a logic low state, data can be transferred from the μC .

CS High to low transition:



- ·Serial input data can be clocked in from then on
- •SO changes from high impendance state to logic high or low state corresponding to the SO bit-state

CS Low to high transition:



- •Transfer of SI bits from shift register into output buffers, if number of clock signals was an integer multiple of 8
- •SO changes from the SO bit-state to high impendance state

To avoid any false clocking the serial input pin SCLK should be logic high state during high-to-low transition of $\overline{\text{CS}}$. When $\overline{\text{CS}}$ is in a logic high state, any signals at the SCLK and SI pins are ignored and SO is forced into a high impedance state. The integrated modulo counter that counts the number of clocks avoids the take over of invalid commands caused by a spike on the clock line or wrong number of clock cycles. A command is only taken over if after the low-to-high transition of the $\overline{\text{CS}}$ signal the number of counted clock cycles is an integer multiple of 8.

SCLK - Serial clock. The system clock pin clocks the internal shift register of the ISO1H816G. The serial input (SI) accepts data into the input shift register on the rising edge of SCLK while the serial output (SO) shifts the output information out of the shift register on the falling edge of the serial clock. It is essential that the SCLK pin is in a logic high state whenever chip select CS makes any transition. The number of clock pulses will be counted during a chip select cycle. The received data will only be accepted, if exactly an integer multiple of 8 clock pulses were counted during CS is active.

- **SI** Serial input. Serial data bits are shifted in at this pin, the most significant bit first. SI information is read in on the rising edge of the SCLK. Input data is latched in the shift register and then transferred to the control buffer of the output stages.
- ${
 m SO}$ Serial output. SO is in a high impedance state until the $\overline{\rm CS}$ pin goes to a logic low state. The data of the internal shift register are shifted out serially at this pin. The most significant bit will appear at first. The further bits will appear following the falling edge of SCLK.

3.5.2 SPI Bus Concepts

3.5.2.1 Independent Individual Control

Each IC with a SPI is controlled individually and independently by an SPI master, as in a directional point-to-point communication. The port requirements for this topology are the greatest, because for each controlled IC an individual SPI at the μC is needed (SCLK, \overline{CS} , SI). All ICs can be addressed simultaneously with the full SPI bandwidth.

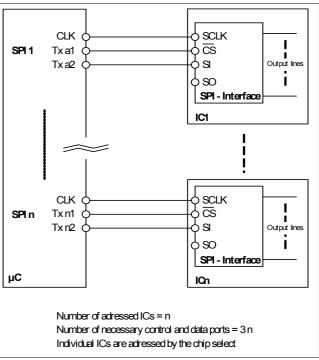


Figure 9 Individual independent control of each IC with SPI

3.5.2.2 Daisy-chain Configuration

The connection of different ICs and a μ C as shown in Fig. 11 is called a daisy-chain. For this type of bustopology only one SPI interface of the μ C for two or



more ICs is needed. All ICs share the same clock and chip select port of the SPI master. That is all ICs are active and addressed simultaneously. The data out of the μC is connected to the SI of the first IC in the line. Each SO of an IC is connected to the SI of the next IC in the line.

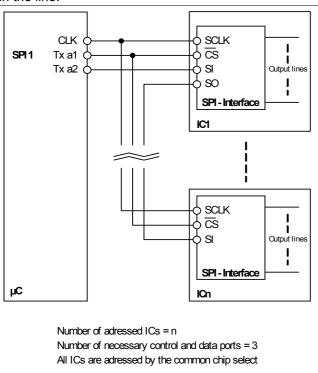


Figure 10 SPI bus all ICs in a "daisy chain" configuration

The µC feeds to data bits into the SI of IC1 (first IC in the chain). The bits coming from the SO of IC1 are directly shifted into the SI of the next IC. As long as the chip select is inactive (logic high) all the IC SPIs ignore the clock (SCLK) and input signals (SI) and all outputs (SO) are in tristate. As long as the chip select is active the SPI register works as a simple shift register. With each clock signal one input is shifted into the SPI register (SI), each bit in the shift register moves one position further within the register, and the last bit in the SPI shift register is shifted out of SO. This continous as long as the chip select is active (logic low) and clock signals are applied. The data is then only taken over to the output buffers of each IC when the CS signal changes to high from low and recognized as valid data by the internal modulo counter.

3.6 Transmission Failure Detection

There is a failure detection unit integrated to ensure also a stable functionality during the integrated coreless transformer transmission. This unit decides wether the transmitted data is valid or not. If four times serial data coming from the internal registers is not accepted the output stages are switched off until the next valid data is received.



3.7 Serial Interface Timing

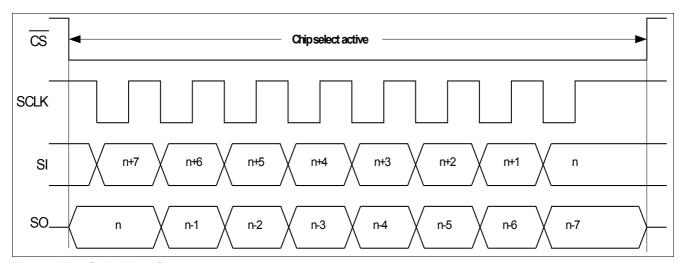


Figure 11 Serial interface

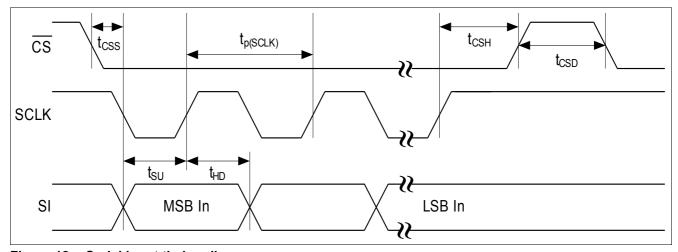


Figure 12 Serial input timing diagram

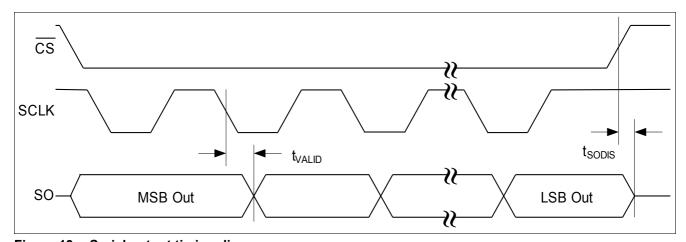


Figure 13 Serial output timing diagram



4 Electrical Characteristics

Note: All voltages at pins 2to 14 are measured with respect to ground GNDCC (pin 15). All voltages at pin 20 to pin 36 and TAB are measured with respect to ground GNDbb (pin 19). The voltage levels are valid if other ratings are not violated. The two voltage domains V_{CC} , GND_{CC} and V_{bb} , GND_{bb} are internally galvanic isolated.

4.1 Absolute Maximum Ratings

Note: Absolute maximum ratings are defined as ratings, which when being exceeded may lead to destruction of the integrated circuit. For the same reason make sure, that any capacitor that will be connected to pin 2 (VCC) and TAB (Vbb) is discharged before assembling the application circuit. Supply voltages higher than V_{bb(AZ)} require an external current limit for the GNDbb pin, e.g. with a 15Ω resistor in GNDbb connection. Operating at absolute maximum ratings can lead to a reduced lifetime.

Parameter	Symbol	Limit Values				
at T_j = -40 135°C, unless otherwise specified		min.	max.			
Supply voltage input interface (VCC)	V _{CC}	-0.5	6.5	V		
Supply voltage output interface (Vbb)	V _{bb}	-1 ¹⁾	45			
Continuos voltage at pin SI	V _{Dx}	-0.5	6.5			
Continuos voltage at pin CS	V _{CS}	-0.5	6.5			
Continuos voltage at pin SCLK	V _{WR}	-0.5	6.5			
Continuos voltage at pin DIS	V _{DIS}	-0.5	6.5			
Continuos voltage at pin SO	V _{Dx}	-0.5	6.5			
Continuos voltage at pin DIAG	V _{DIAG}	-0.5	6.5			
Load current (short-circuit current)	IL		self limited	Α		
Reverse current through GNDbb ¹⁾	I _{GNDbb}	-1.6				
Operating Temperature	Tj	-25	internal limited	°C		
Extended Operation Temperature ²⁾	T _j	-40	internal limited			
Storage Temperature	T _{stg}	-50	150			
Power Dissipation ³⁾	P _{tot}		3.3	W		
Inductive load switch-off energy dissipation ⁴⁾ single pulse, $T_j = 125^{\circ}$ C, $I_L = 1.2$ A one channel active all channel simultaneously active (each channel)	E _{AS}		10 1	J		
Load dump protection ³⁾ $V_{loadDump}^{5)}=V_A + V_S$ V_{IN} = low or high t_d = 400ms, R_I = 2W, R_L = 27W, V_A = 13.5V t_d = 350ms, R_I = 2W, R_L = 57W, V_A = 27V	V _{Loaddump}		90 117	V		
Electrostatic discharge voltage (Human Body Model) according to JESD22-A114-B	V _{ESD}		2	kV		
Electrostatic discharge voltage (Charge Device Model) according to ESD STM5.3.1 - 1999	V _{ESD}		1	kV		
Continuos reverse drain current ¹⁾³⁾ , each channel	Is		4	Α		

¹⁾ defined by P_{tot}

²⁾ not subject to production test, slight deviation of electrical parameters possible.

³⁾ Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thick) copper area for drain connection. PCB is vertical without blown air.



- 4) not subject to production test, specified by design
- 5) $V_{Loaddump}$ is setup without the DUT connected to the generator per ISO7637-1 and DIN40839

4.2 Thermal Characteristics

Parameter	Symbol Limit Value		Limit Values			Limit Values L		mbol Limit Values		Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} = 3.05.5V, unless otherwise specified		min.	typ.	max.							
Thermal resistance junction - case	R _{thJC}			1.5	K/W						
Thermal resistance @ min. footprint	$R_{th(JA)}$			50							
Thermal resistance @ 6cm² cooling area ¹⁾	R _{th(JA)}			38							

¹⁾ Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thick) copper area for drain connection. PCB is vertical without blown air.

Datasheet 14 Revision 2.2, 2013-01-31



4.3 Load Switching Capabilities and Characteristics

Parameter	Symbol	Li	mit Valu	es	Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} = 3.05.5V, unless otherwise specified		min.	typ.	max.		
On-state resistance, $I_L = 0.5A$, each channel $T_j = 25^{\circ}C$ $T_j = 125^{\circ}C$ two parallel channels, $T_j = 25^{\circ}C$:	R _{ON}		150 270 75	200 320 100	mΩ	
four parallel channels, $T_j = 25^{\circ}C^{:1)}$ Nominal load current Device on PCB 38K/W, $T_a = 85^{\circ}C$, $T_j < 125^{\circ}C$ one channel: ¹⁾ two parallel channels: ¹⁾ four parallel channels: ¹⁾	I _{L(NOM)}		1.4 2.2 4.4	50	A	
Turn-on time to 90% $V_{OUT}^{(2)}$ $R_L = 47\Omega$, $V_{Dx} = 0$ to 5V	t _{on}		64	120	μs	
Turn-off time to 10% $V_{OUT}^{(1)}$ $R_L = 47\Omega$, $V_{Dx} = 5$ to 0V	t _{off}		89	170		
Slew rate on 10 to 30% V_{OUT} R _L = 47 Ω , V_{bb} = 15 V	dV/dt _{on}		1	2	V/µs	
Slew rate off 70 to 40% V_{OUT} R _L = 47 Ω , V_{bb} = 15 V	-dV/dt _{off}		1	2		

¹⁾ not subject to production test, specified by design

4.4 Operating Parameters

Parameter		Symbol	Li	mit Valu	es	Unit	Test Condition	
at $T_j = -25 125$ °C, 3.05.5V, unless oth			min.	typ.	max.			
Common mode trans	sient immunity ¹⁾	dV _{ISO} /dt	-25	-	25	kV/μs	DV _{ISO} = 500V	
Magnetic field immur	nity ¹⁾	H _{IM}	100			A/m	IEC61000-4-8	
Voltage domain V _{bb}	Operating voltage	V _{bb}	11		35	V		
(Output interface)	Undervoltage shutdown	V _{bb(under)}	7		10.5			
	Undervoltage restart	V _{bb(u_rst)}			11			
	Undervoltage hysteresis	$\Delta V_{bb(under)}$		0.5				
	Undervoltage current	I _{bb(uvlo)}		1	2.5	mA	V _{bb} < 7V	
	Operating current	I _{GNDL}		10	14	mA	All Channels ON - no load	
	Leakage output current (included in $I_{bb(off)}$) $V_{Dx} = Iow$, each channel	I _{L(off)}		5	30	μΑ		

²⁾ The turn-on and turn-off time includes the switching time of the high-side switch and the transmission time via the coreless transformer in normal operating mode. During a failure on the coreless transformer transmission turn-on or turn-off time can increase by up to 50µs.



Voltage domain V _{CC} (Input interface)	Operating voltage	V _{CC}	3.0		5.5	V	
	Undervoltage shutdown	V _{CC(under)}	2.5		2.9		
	Undervoltage restart	V _{CC(u_rst)}			3		
	Undervoltage hysteresis	$\Delta V_{CC(under)}$		0.1			
	Undervoltage current	I _{CC(uvlo)}		1	2	mA	V _{cc} < 2.5V
	Operating current	I _{CC(on)}		4.5	6	mA	

¹⁾ not subject to production test

4.5 Output Protection Functions

Parameter ¹⁾	Symbol	Liı	mit Valu	es	Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} =3.05.5V, unless otherwise specified		min.	typ.	max.		
Initial peak short circuit current limit, each channel T_j = -25°C, V_{bb} = 30V, t_m = 700 μ s T_i = 25°C	I _{L(SCp)}			4.5	A	
$T_i = 125$ °C			3.0			
two parallel channels: ³⁾		1.4				
four parallel channels: ³⁾			current of on he current of			
Repetitive short circuit current limit ³⁾ T _i = T _{it} (see timing diagrams)	I _{L(SCr)}					
each channel: two parallel channels: ³⁾ four parallel channels: ³⁾			2.2 2.2 2.2			
Output clamp (inductive load switch off) at $V_{OUT} = V_{bb} - V_{ON(CL)}$	V _{ON(CL)}	47	53	60	V	
Overvoltage protection	$V_{bb(AZ)}$	47				
Thermal overload trip temperature ^{2) 3)}	T _{jt}	135			°C	
Thermal hysteresis ³⁾	ΔT_{jt}		10		K	

¹⁾ Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuos repetitive operation.

4.6 Diagnostic Characteristics at pin DIAG

Parameter	Symbol Limit Values				Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} =3.05.5V, unless otherwise specified		min.	typ.	max.		
Common diagnostic sink current (overtemperature of any channel) $T_j = 135$ °C	I _{diagsink}			5	mA	V _{DIAGON} < 0.25 x VCC
Common diagnostic source current	Idiagsource		100		μΑ	

²⁾ Higher operating temperature at normal function for each channel available

³⁾ not subject to production test, specified by design



4.7 Input Interface

Parameter	Symbol	Liı	Limit Values		Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} = 3.05.5V, unless otherwise specified		min.	typ.	max.		
Input low state voltage (SI, DIS, CS, SCLK)	V _{IL}	-0.3		0.3 x V _{CC}	V	
Input high state voltage (SI, DIS, CS, SCLK)	V _{IH}	0.7 x V _{CC}		V _{CC} + 0.3		
Input voltage hysteresis (SI, DIS, CS, SCLK)	V _{IHys}		100		mV	
Output low state voltage (SO)	V _{OL}	-0.3		0.25 x V _{CC}	٧	$C_L < 50pF,$ $R_L > 10k\Omega$
Output high state voltage (SO)	V _{OH}	0.75 x V _{CC}		V _{CC} + 0.3		
Input pull down current (SI , DIS)	I _{Idown}		100		μA	
Input pull up current (CS, SCLK)	-I _{lup}		100			
Output disable time (transition \overline{DIS} to logic low) ¹⁾²⁾ Normal operation Turn-off time to 10% V_{OUT} $R_L = 47\Omega$	t _{DIS}		85	170	μs	
Output disable time (transition \overline{DIS} to logic low) ¹⁾²⁾³⁾ Disturbed operation Turn-off time to 10% V_{OUT} R_L = 47 Ω	t _{DIS}			230		

- 1) The time includes the turn-on/off time of the high-side switch and the transmission time via the coreless transformer.
- 2) If Pin DIS is set to low the outputs are set to low; after DIS set to high a new write cycle is necessary to set the output again.
- 3) The parameter is not subject to production test verified by design/characterization



4.8 SPI Timing

Parameter	Symbol	Li	mit Valu	ies	Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} = 3.05.5V, unless otherwise specified		min.	typ.	max.		
Serial clock frequency	f _{SCLK}	DC		20	MHz	
Serial clock period (1/fclk)	t _{p(SLCK)}	50			ns	
CS Setup time (falling edge of CS to falling edge of SCLK)	t _{CSS}	5				
$\overline{\text{CS}}$ Hold time (rising edge of SCLK to rising edge of $\overline{\text{CS}}$)	t _{CSH}	10				
Data setup time (required time SI to rising edge of SCLK)	t _{SU}	6				
Data hold time (falling edge of SCLK to SI)	t _{HD}	6				
SO Output valid time CL = 50pF	t _{VALID}			20		
CS Disable time (CS high time between two accesses)	t _{CSD}	20			μs	
SO Output disable time	t _{SODIS}			20	ns	

4.9 Reverse Voltage

Parameter	Symbol	Limit Values			Unit	Test Condition
at T_j = -25 125°C, V_{bb} =1530V, V_{CC} = 3.05.5V, unless otherwise specified		min.	typ.	max.		
Reverse voltage ¹⁾²⁾	-V _{bb}				V	
$R_{GND} = 0 \Omega$	22			1		
$R_{GND} = 150 \Omega$				45		
Diode forward on voltage IF = 1.25A, V _{Dx} = low, each channel	-V _{ON}			1.2		

¹⁾ defined by P_{tot}

²⁾ not subject to production test, specified by design



4.10 Isolation and Safety-Related Specification

Parameter	Value	Unit	Conditions
Rated dielectric isolation voltage V _{ISO}	500	V _{AC}	1 - minute duration ¹⁾
Short term temporary overvoltage	1250	V	5s acc. DIN EN60664-1 1)
Minimum external air gap (clearance)	2.6	mm	shortest distance through air.
Minimum external tracking (creepage)	2.6	mm	shortest distance path along body.
Minimum Internal Gap	0.01	mm	Insulation distance through insulation

¹⁾ not subject to production test, verified by characterization; Production Test with 1100V, 100ms duration

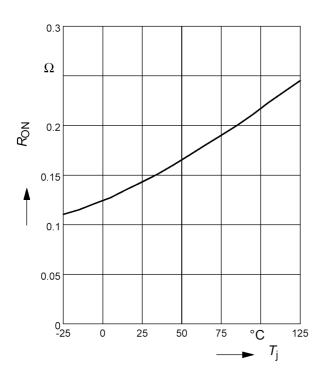
4.11 Reliability

For Qualification Report please contact your local Infineon Technologies office!



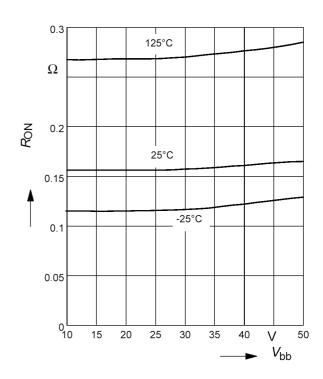
Typ. on-state resistance

$$R_{ON} = f(T_j)$$
; $V_{bb} = 15V$; $V_{in} = high$



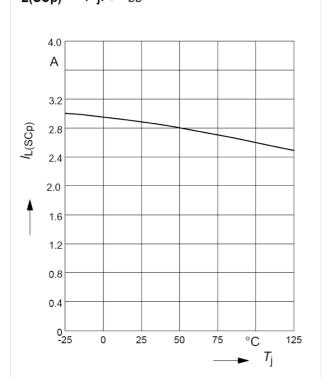
Typ. on-state resistance

$$R_{ON} = f(V_{bb}); I_{L} = 0.5A; V_{in} = high$$



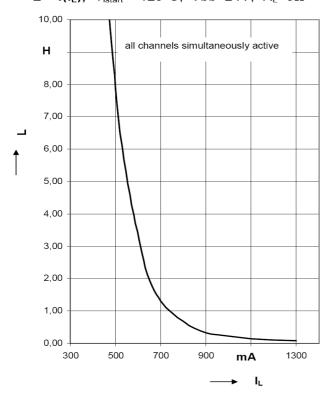
Typ. initial peak short circuit current limit

$$I_{L(SCp)} = f(T_j)$$
; $V_{bb} = 24V$



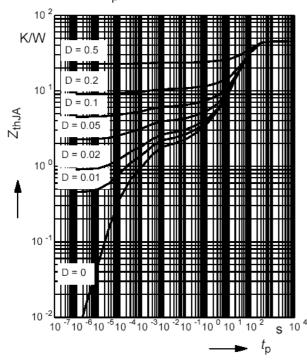


Maximum allowable load inductance for a single switch off, calculated $L = f(I_L)$; $T_{istart} = 125^{\circ}C$, Vbb=24V, $R_L=0\Omega$

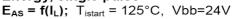


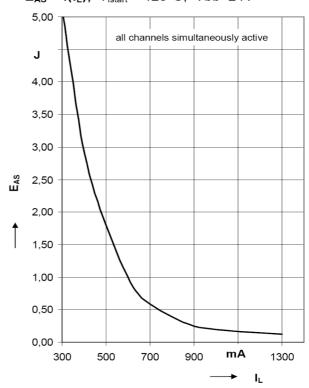
Typ. transient thermal impedance $Z_{\rm thJA} = f(t_{\rm p})$ @ min. footprint

Parameter: $D=t_p/T$



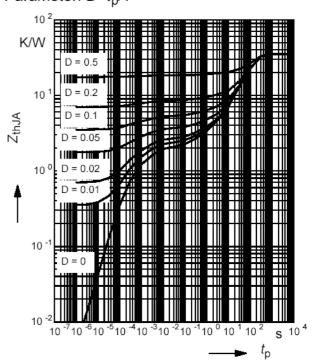
Maximum allowable inductive switch-off Energy, single pulse





Typ. transient thermal impedance Z_{thJA} =f(t_{p}) @ 6cm² heatsink area

Parameter: $D=t_p/T$



Datasheet 21 Revision 2.2, 2013-01-31



Package Outlines

5 Package Outlines

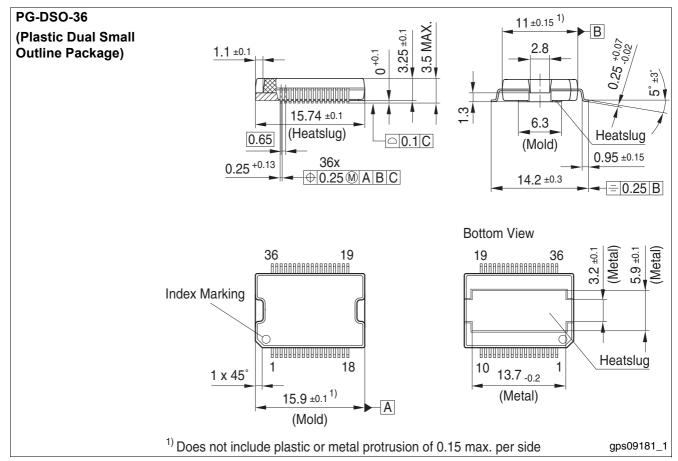


Figure 14 PG-DSO36

www.infineon.com



Компания «ЭлектроПласт» предлагает заключение долгосрочных отношений при поставках импортных электронных компонентов на взаимовыгодных условиях!

Наши преимущества:

- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001:
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits, General Dynamics и др.);

Помимо этого, одним из направлений компании «ЭлектроПласт» является направление «Источники питания». Мы предлагаем Вам помощь Конструкторского отдела:

- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



Как с нами связаться

Телефон: 8 (812) 309 58 32 (многоканальный)

Факс: 8 (812) 320-02-42

Электронная почта: org@eplast1.ru

Адрес: 198099, г. Санкт-Петербург, ул. Калинина,

дом 2, корпус 4, литера А.